BLF25M612

Power LDMOS transistor Rev. 1 — 5 June 2012

Objective data sheet

1. **Product profile**

1.1 General description

12 W LDMOS power transistor for Industrial, Scientific and Medical (ISM) applications at frequencies from 2400 MHz to 2500 MHz.

The BLF25M612 is a driver designed for high power CW applications and is assembled in a high performance ceramic package.

Table 1. Typical performance

RF performance at T_{case} = 25 °C in a common source class-AB production test circuit.

| Test signal | f | V _{DS} | P _{L(AV)} | Gp | η_{D} |
|-------------|-------|-----------------|--------------------|------|------------|
| | (MHz) | (V) | (W) | (dB) | (%) |
| CW | 2450 | 28 | 12 | 19 | 60 |

1.2 Features and benefits

- High efficiency
- High power gain
- Excellent ruggedness
- Excellent thermal stability
- Integrated ESD protection
- Designed for broadband operation (2400 MHz to 2500 MHz)
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

Industrial, scientific and medical applications in the frequency range 2400 MHz to 2500 MHz



Power LDMOS transistor

2. Pinning information

Table 2. Pinning

| | 9 | |
|-----|-------------|-----------------------------------|
| Pin | Description | Simplified outline Graphic symbol |
| 1 | drain | |
| 2 | gate | |
| 3 | source | [1] 2 3 3 sym112 |

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

| Type number | Package | Package | | | |
|-------------|---------|--|---------|--|--|
| | Name | Description | Version | | |
| BLF25M612 | - | earless flanged ceramic package; 2 leads | SOT975B | | |

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|----------------------|------------|------|-----|------|
| V_{DS} | drain-source voltage | | - | 65 | V |
| V_{GS} | gate-source voltage | | -0.5 | +13 | V |
| T _{stg} | storage temperature | | -65 | - | °C |
| T _i | junction temperature | | - | 225 | °C |

5. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Тур | Unit |
|-------------------------|--|----------------------------------|-----|------|
| $R_{\text{th(j-case)}}$ | thermal resistance from junction to case | T_{case} = 80 °C; P_L = 12 W | 4.0 | K/W |

6. Characteristics

Table 6. Characteristics

 $T_i = 25$ °C per section; unless otherwise specified.

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|----------------------------------|---|-----|-----|-----|------|
| $V_{(BR)DSS}$ | drain-source breakdown voltage | $V_{GS} = 0 \text{ V}; I_D = 0.18 \text{ mA}$ | 65 | - | - | V |
| V _{GS(th)} | gate-source threshold voltage | $V_{DS} = 10 \text{ V}; I_D = 18 \text{ mA}$ | 1.4 | 1.9 | 2.4 | V |
| I _{DSS} | drain leakage current | $V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$ | - | - | 1.4 | μΑ |
| I _{DSX} | drain cut-off current | $V_{GS} = V_{GS(th)} + 3.75 V;$ $V_{DS} = 10 V$ | - | 3.2 | - | Α |
| I_{GSS} | gate leakage current | $V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$ | - | - | 140 | nΑ |
| g _{fs} | forward transconductance | $V_{DS} = 10 \text{ V}; I_{D} = 0.9 \text{ A}$ | - | 1.3 | - | S |
| R _{DS(on)} | drain-source on-state resistance | $V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 0.6 \text{ A}$ | - | 8.0 | 1.3 | Ω |

Table 7. Application information

Test signal: CW at f = 2450 MHz; RF performance at $V_{DS} = 28$ V; $I_{Dq} = 10$ mA; $T_{case} = 25$ °C; unless otherwise specified; in a class-AB production test circuit.

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|------------|-------------------|-----------------------|-----|-----|-----|------|
| G_p | power gain | $P_L = 12 W$ | 18 | 19 | - | dB |
| RL_{in} | input return loss | P _L = 12 W | - | -14 | -10 | dB |
| η_{D} | drain efficiency | P _L = 12 W | 55 | 60 | - | % |

7. Test information

7.1 Ruggedness in class-AB operation

The BLF25M612 is capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 28 V; I_{Dq} = 10 mA; P_{L} = 12 W (CW); f = 2450 MHz.

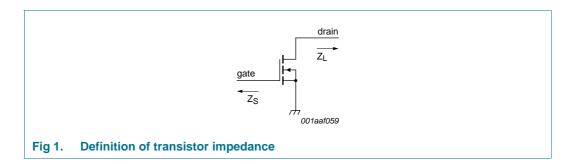
7.2 Impedance information

Table 8. Typical impedance

Measured load-pull data. Typical values unless otherwise specified.

| f | Z _S | Z _L |
|-------|----------------|----------------|
| (MHz) | (Ω) | (Ω) |
| 2400 | 3.1 – 10.1j | 3.8 – 1.4j |
| 2450 | 4.0 – 10.7j | 3.4 – 2.1j |
| 2500 | 5.6 – 8.9j | 4.5 – 1.9j |

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7.3 Test circuit

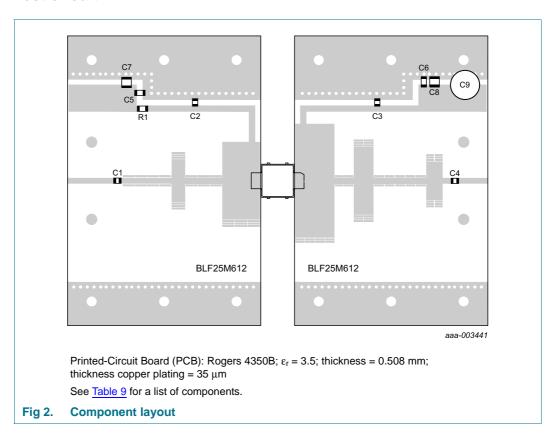
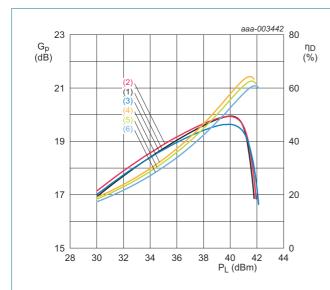


Table 9. List of components For test circuit see Figure 2.

| Component | Description | Value Remark | |
|----------------|-----------------------------------|---------------|----------|
| C1, C2, C3, C4 | multilayer ceramic chip capacitor | 15 pF ATC100A | |
| C5, C6 | multilayer ceramic chip capacitor | 220 nF | SMD 1206 |
| C7, C8 | multilayer ceramic chip capacitor | 4.7 μF; 50 V | |
| C9 | electrolytic capacitor | 100 μF; 63 V | |
| R1 | SMD resistor | 7.5 Ω | SMD 0805 |

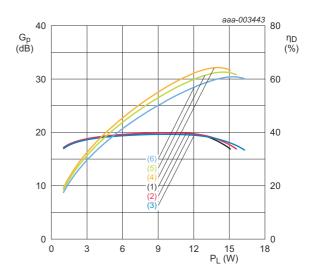
7.4 Graphical data



 $V_{DS} = 28 \text{ V}; I_{Dq} = 10 \text{ mA}.$

- (1) G_p at f = 2400 MHz
- (2) G_p at f = 2450 MHz
- (3) G_p at f = 2500 MHz
- (4) η_D at f = 2400 MHz
- (5) η_D at f = 2450 MHz
- (6) η_D at f = 2500 MHz

Fig 3. Power gain and drain efficiency as function of load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 10 \text{ mA}.$

- (1) G_p at f = 2400 MHz
- (2) G_p at f = 2450 MHz
- (3) G_p at f = 2500 MHz
- (4) η_D at f = 2400 MHz
- (5) η_D at f = 2450 MHz
- (6) η_D at f = 2500 MHz

Fig 4. Power gain and drain efficiency as function of load power; typical values

8. Package outline

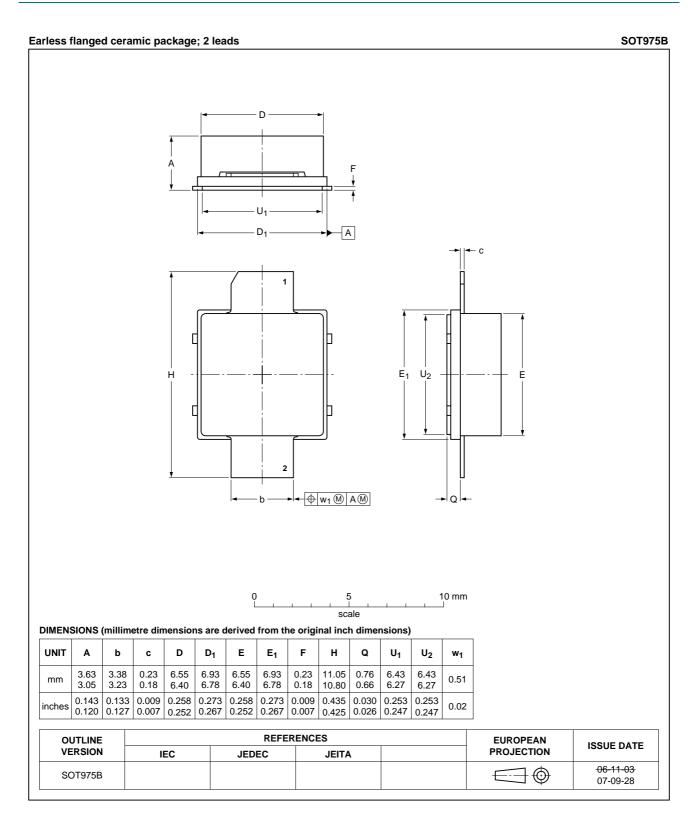


Fig 5. Package outline SOT975B

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9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

| Acronym | Description |
|---------|--|
| CW | Continuous Wave |
| ESD | ElectroStatic Discharge |
| LDMOS | Laterally Diffused Metal-Oxide Semiconductor |
| VSWR | Voltage Standing-Wave Ratio |

11. Revision history

Table 11. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|---------------|--------------|----------------------|---------------|------------|
| BLF25M612 v.1 | 20120605 | Objective data sheet | - | - |

12. Legal information

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|--------------------------------|-------------------|---|
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